Elektronenstrahl - Mikrosonde (EMS)

JEOL JXA 8200

Bes	schreibung:					JXA 82 de in u	ltramafischen C	esteine	n			7
Qu	antitative A	nalysi	s Ai	nalyse	nprogramm = SAN	MPLE	(Meas. + Std. + St	g. Conditi	ions)			
jx1 USER ACC. Voltage Beam		20kV GROUP					DejanU SAMPLE					
		30 nA			Aperturblende 1		fix. Elements	-				
		Sta	ndard Anal	ysis	St	andar	d = SAMPLE (Me	eas. + St	g. Conditions)			OS Chan
Nr	Element Linie	Val	Mem	Block	Standardname	.cond	NetInt. / DL cps / ppm	1	2	3 OS Krista	4	5
1	Al Ka	3	1	a	aAl ₂ O ₃	20	26500 / 35	T	P	P	L	LI
2	Cr Ka	3	1	a	aCr ₂ O ₃	20	23140 / 50		WDS Elemente			
3	Fe Ka	2	1	a	aFe ₂ O ₃	20	5802 / 144	Mg	Si	Ca	Mn	C
4	Ni Ka	2	1	a	aNiO	20	30140 / 60	Al	Ti	Cr	Fe	N
5	Mn Ka	2	1	a	aRhodonit	20	2050 / 100		V			
6	Ti Ka	4	1	a	aTiO ₂	20	15100 / 90					
7	V Ka	3	1	a	aV	20	24980 / 100					
8	Ca Ka	2	1	a	aWOLLA	20	10460 / 45					
9	Co Ka	2	1	b	bCOBALTIN	20	12300 / 35	Korrektur: Oxide ZAF				
10	Mg Ka	4	1	b	bOLIV	20	8956 / 144	Overlaps: TiK>VK=0.0651				
11	Si Ka	4	1	b	bOLIV	20	1111 / 170	V>Cr=0,1676, FeKa>CoKa=0,00704,				
12								CrKa>I	MnKa=0	.000154		
13								Kommentar				
14								Kalibrie	erung m	it 20kV,	20nA	
15												
16												
17												
18												
19								Datum Bearbeiter				
20	pfohlene Me							27.07.2	017			

Empfohlene Messzeiten **PEAK:** UNKsec (STDsec * n points)
Al 160 (10*4) – Cr 60(10*4) – Fe 20(20*4) – Mg 15(20*4) – Ni 50(10*4) – Mn 50(30*5) – Ti 50(15*5) – V 50(10*5)
Ca 50(15*4) – Si 30(40*5) – Co 40(25*5)